Serial Number: 10/674,593 Filing Date: September 29, 2003

Title: METHOD AND APPARATUS FOR CHANNEL-BASED TESTING

Assignee: Intel Corporation

IN THE CLAIM

The pending claims are as follows:

- 1-4. (Canceled)
- 5. (Previously Presented) A method of testing a driver comprising:

driving a known reference channel with the driver, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and comparing a measurement against a requirement to determine if the driver passes a test.

- 6. (Original) The method of claim 5 wherein the method is performed by computer simulation.
- 7. (Previously Presented) The method of claim 6 wherein the known reference channel is specified by s-parameters.
- 8. (Canceled)
- 9. (Previously Presented) The method of claim 5 wherein the known reference channel is further specified by a minimum delay.
- 10. (Previously Presented) The method of claim 5 wherein the known reference channel is further specified by a maximum delay.
- 11. (Original) The method of claim 5 wherein the at least one parameter includes an eye voltage.

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12. (Original) The method of claim 5 wherein the at least one parameter includes an eye time.

- 13. (Canceled)
- 14. (Previously Presented) A method comprising:

coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and comparing a measurement against a requirement to determine if the device under test passes a test.

- 15. (Original) The method of claim 14 wherein the device under test comprises a receiver.
- 16. (Original) The method of claim 14 wherein the device under test comprises a driver.
- 17. (Original) The method of claim 14 wherein the at least one parameter comprises an eye voltage.
- 18. (Original) The method of claim 14 wherein the at least one parameter comprises an eye time.
- 19. (Original) The method of claim 14 wherein the method is performed by computer simulation.
- 20. (Previously Presented) The method of claim 19 wherein the known reference channel is defined by a set of reference channel parameters.

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21. (Original) The method of claim 20 wherein the set of reference channel parameters comprises s-parameters.

- 22. (Canceled)
- 23. (Previously Presented) The method of claim 20 wherein the set of reference channel parameters comprises a delay value.
- 24. (Previously Presented) An apparatus including a medium adapted to hold machine-accessible instructions that when accessed result in a machine performing:

coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

measuring at least one parameter at an output of the known reference channel; and comparing a measurement against a requirement to determine if the device under test passes a test.

- 25. (Original) The apparatus of claim 24 wherein the device under test comprises a receiver.
- 26. (Original) The apparatus of claim 24 wherein the device under test comprises a driver.
- 27. (Original) The apparatus of claim 24 wherein the at least one parameter comprises an eye time.
- 28. (Previously Presented) An electronic system comprising:a processor capable of simulating a circuit; andan SRAM storage medium accessible by the processor, the storage medium to hold

instructions that when accessed result in the processor performing:

AMENDMENT AND RESPONSE UNDER 37 CFR § 1.116

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coupling a device under test to a known reference channel, wherein the known reference channel is specified as a worst-case channel that displays a maximum allowable loss versus frequency characteristic;

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measuring at least one parameter at an output of the known reference channel; and comparing a measurement against a requirement to determine if the device under passes a test.

- 29. (Original) The electronic system of claim 28 wherein the device under test comprises a receiver.
- 30. (Original) The electronic system of claim 28 wherein the device under test comprises a driver.